

# AR-TTA: A Simple Method for Real-World Continual Test-Time Adaptation



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## Introduction

- Current machine learning models perform very well only when the test-time distribution is close to the training-time distribution.
- Continual Test-Time Adaptation (TTA) methods allow the source model to adapt itself on-the-fly to continual changes in data distribution without any supervision.
- Current techniques are usually evaluated on benchmarks that are only a simplification of real-world scenarios.
- We observe that current test-time adaptation methods struggle to effectively handle varying degrees of domain shift, often resulting in degraded performance that falls below that of the

# 100 90 90 80 70 60 50 Source TENT COTTA EATA SAR AR-TTA (Ours)

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Figure 1. Continual test-time adaptation methods evaluated on synthetic (CIFAR-10C) and realistic (CLAD-C) domain shifts. Our method is the only one that consistently allows to improve over the naive strategy of using the (frozen) source model.

#### **Results on natural domain shifts**

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Table 2. Classification accuracy and average mean class accuracy (AMCA) (%) for the CLAD-C continual test-time adaptation task.

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Method	T1	Τ2	ТЗ	T4	Τ5	Mean day	Mean night	Mean	AMCA
Source	75.6	85.9	73.3	87.5	66.2	86.6	71.2	81.3	57.6
BN stats adapt	73.2	69.9	75.0	75.5	59.7	72.2	69.1	71.1	48.3
TENT-continual [6]	73.4	69.8	76.5	76.1	59.7	72.4	69.8	71.5	47.6
EATA [2]	73.3	69.9	75.0	75.6	59.7	72.2	69.1	71.1	48.4
CoTTA [7]	75.2	69.3	80.2	77.0	62.7	72.4	72.9	72.6	44.8
SAR [3]	73.2	69.9	75.0	75.5	59.7	72.2	69.1	71.1	48.3
Ours (AR-TTA) w/o replay	76.9	86.7	81.4	87.9	73.5	87.2	77.1	<b>83.9</b> <sub>±0.30</sub>	$59.6_{\pm 2.92}$
Ours (AR-TTA)	77.2	86.7	80.0	89.6	70.7	87.8	75.7	$83.7_{\pm 0.64}$	$63.1_{\pm 3.32}$

Table 3. Classification accuracy and average mean class accuracy (AMCA) (%) for the SHIFT-C continual test-time adaptation task.



source model.

## Contribution

Our main contributions can be summarized as follows:

- We evaluate and analyze current test-time adaptation methods on realistic, continual domain shift image classification data from autonomous driving.
- We propose a simple continual TTA method.
- Extensive evaluation shows that the proposed method obtains state-of-the-art performance on multiple benchmarks with both artificial distortions and real-life domain shifts.

## Natural domain shifts





Figure 2. Example images from various domains within the CLAD-C benchmark.

- Figure 3. Example images with different corruptions from the ImageNet-C dataset.
- The most popular setting for test-time adaptation includes using different classes of synthetic corruptions.
- In practical applications, the target distribution can easily change in different manner, perpetually over time, e.g., due to changing weather, lighting conditions, or traffic intensity.
- Hence, we propose to use two benchmarks that consist of data with domain shifts that can occur in real-world applications - the CLAD-C benchmark [5] and the SHIFT dataset [4].

# **Proposed method (AR-TTA)**

Method	NDN	rcast	iny	20	Jear	NDN	rcast	iny	SO	JPa	NDN	rcast	'nγ	SO	Mean	AMCA
	C/O	ove,	ľa,	<i>P</i>	5	c/o	ove,	ľa,	10°	C/	C/O	ove,	ľa,	100		
Source	97.9	98.2	97.5	92.5	93.6	94.1	94.0	93.5	91.5	89.1	89.3	90.6	89.1	90.7	93.5	89.5
BN stats adapt	89.1	88.9	88.0	86.2	85.3	84.8	87.3	83.5	84.8	81.3	81.2	80.3	79.6	83.5	85.1	69.9
TENT-continual [6]	89.6	88.8	87.5	84.6	83.3	81.2	85.0	80.7	80.2	78.0	77.0	76.1	75.7	77.6	82.7	57.6
EATA [2]	89.1	88.9	88.0	86.2	85.3	84.8	87.4	83.6	84.9	81.4	81.4	80.3	79.7	83.7	85.1	70.5
CoTTA [7]	88.2	87.1	84.1	80.5	78.7	76.2	80.5	74.0	74.9	71.5	70.3	67.3	64.9	66.2	77.4	47.2
SAR [3]	89.1	88.9	88.0	86.2	85.3	84.8	87.3	83.5	84.8	81.3	81.2	80.3	79.6	83.6	85.1	69.9
Ours (AR-TTA) w/o replay	96.4	96.5	95.3	93.2	92.2	91.9	93.2	91.4	91.8	88.7	88.7	88.6	87.5	91.2	$92.4_{\pm 0.25}$	$83.5_{\pm 0.96}$
Ours (AR-TTA)	97.7	98.0	97.4	94.3	94.2	95.5	94.8	95.2	93.1	92.3	92.7	93.0	91.4	92.6	<b>94.8</b> ±0.03	<b>90.2</b> $_{\pm 0.24}$

- Calculating BN statistics for each batch (BN stats adapt method) does not improve the performance over the frozen source model on natural domain shifts.
- Similarly, the state-of-the-art TTA methods achieve significantly lower mean accuracy, compared to the frozen source model, rendering them not effective for natural domain shifts.
- Our method, which uses pre-calculated statistics and exemplars of source data during adaptation, outperformed state-of-the-art methods and achieves higher accuracy than the source model, which shows the effectiveness and adapting capabilities.
- Average mean class accuracy (AMCA) values show that the usage of replay memory might be crucial for high mean per-class accuracy.







- Update procedure: Inspired by [7], we keep two identical neural network models with different sets of weights: the teacher model and the student model. The student model is updated based on cross-entropy loss between its predictions and pseudo-labels generated by the teacher model. The teacher model is adapted based on an exponential moving average of student's weights. Predictions for each image are taken from the teacher model.
- Experience replay: We store a small class-balanced buffer of random exemplars from the labeled source data in the memory. We sample one exemplar from memory for each test image and mixup image pairs. Similarly, pseudo-labels from the teacher model are mixupped with the labels of sampled exemplars. The student model is trained on augmented test samples and augmented pseudo-labels.
- Dynamic Barch Normalization Statistics: To robustly estimate the correct Batch Normalization (BN) statistics we take the inspiration from [1] and propose to estimate BN statistics during test-time by linearly interpolating between saved statistics of source data and statistics of the current batch. The parameter that weights the influence of two sets of statistics is adjusted by the exponential moving average. Its value at the current batch is calculated using the distance between the distribution of the current batch and the distribution used for the previous batch. As a distance metric, we utilize

Figure 4. Batch-wise classification accuracy averaged in a window of 100 batches on CLAD-C benchmark for the chosen methods continually adapted to the sequences of data. The ticks on x-axis symbolize the beginning of next sequence and at the same time a different domain. Window for calculating average values is cleared in between sequences.

#### Conclusions

- State-of-the-art methods are inadequate in real-life settings, as they fall short in achieving accuracy comparable to the frozen source model.
- We propose a novel and straightforward method called AR-TTA. It achieves state-of-the-art performance on various benchmarks, consistently outperforming the source model, which serves as the ultimate baseline for feasible TTA methods.
- Our more realistic evaluation of TTA with a variety of different datasets provides a better understanding of their potential benefits and shortcomings.

#### References

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#### symmetric KL divergence.

### **Results on artificial domain shifts**

Table 1. Classification accuracy (%) for the standard ImageNet-to-ImageNetC and CIFAR10-to-CIFAR10C online continual test-time adaptation tasks.

Mathad	Mean						
Method	CIFAR10C	ImageNetC					
Source	56.5	18.1					
BN stats adapt	75.0	26.9					
TENT-continual [6]	76.7	29.2					
EATA [2]	78.2	31.5					
COTTA [7]	75.7	15.5					
SAR [3]	75.2	30.8					
Ours (AR-TTA) w/o replay	$77.3_{\pm 0.07}$	$30.0_{\pm 0.45}$					
Ours (AR-TTA)	<b>78.8</b> $\pm 0.13$	$32.0_{\pm 0.07}$					

 Artificial domain shifts pose a great challenge for source model.

- Discarding BN statistics calculated on the source training data and estimating them for each batch separately, already significantly improves the result on corrupted images (BN stats adapt method).
- Each of the compared state-of-the-art TTA methods uses the BN stats adapt technique, therefore they are able to improve over it, but the increase in accuracy value is not that significant.
- Our method AR-TTA outperforms all of the compared techniques.

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